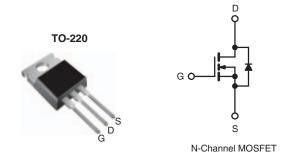


Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	400	400 V			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	1.8			
Q _g (Max.) (nC)	2	20			
Q _{gs} (nC)	3	3.3			
Q _{gd} (nC)	1	11			
Configuration	Sin	Single			



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available



DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
Lead (Pb)-free	IRF720PbF
Lead (FD)-liee	SiHF720-E3
SnPb	IRF720
GIII D	SiHF720

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, unless otherw	rise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	400	V		
Gate-Source Voltage	V_{GS}	± 20	V		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		3.3	А	
	V_{GS} at 10 V $T_C = 100 ^{\circ}C$	I _D	2.1		
Pulsed Drain Current ^a	I _{DM}	13	1		
Linear Derating Factor		0.40	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	190	mJ		
Repetitive Avalanche Current ^a	I _{AR}	3.3	Α		
Repetitive Avalanche Energy ^a	E _{AR}	5.0	mJ		
Maximum Power Dissipation	T _C = 25 °C	P _D	50	W	
Peak Diode Recovery dV/dtc	dV/dt	4.0	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d		
Mounting Torque	6 00 or M0 corour		10	lbf ⋅ in	
	6-32 or M3 screw		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 30 mH, R_G = 25 Ω , I_{AS} = 3.3 A (see fig. 12).
- c. $I_{SD} \le 3.3$ A, $dI/dt \le 65$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



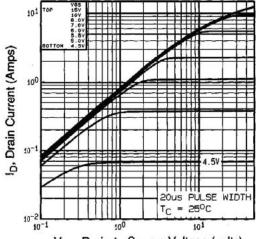
THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5		

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT
Static		<u>.</u>					
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		400	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	o 25 °C, I _D = 1 mA	-	0.51	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{C}$	$V_{DS} = V_{GS}, I_D = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20		-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 400 V, V _{GS} = 0 V		-	-	25	
		V _{DS} = 320 V, V	_{GS} = 0 V, T _J = 125 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.0 A ^b	-	-	1.8	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 50	0 V, I _D = 2.0 A ^b	1.7	-	-	S
Dynamic		·					
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	410	-	pF
Output Capacitance	C _{oss}			-	120	-	
Reverse Transfer Capacitance	C _{rss}			-	47	-	
Total Gate Charge	Qg		V_{GS} = 10 V I_{D} = 3.3 A, V_{DS} = 320 V, see fig. 6 and 13 ^b	-	-	20	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	3.3	
Gate-Drain Charge	Q_{gd}	1		-	-	11	
Turn-On Delay Time	t _{d(on)}			-	10	-	
Rise Time	t _r	V_{DD} = 200 V, I_{D} = 3.3 A R_{G} = 18 Ω , R_{D} = 56 Ω , see fig. 10 ^b		-	14	-	ns
Turn-Off Delay Time	t _{d(off)}			-	30	-	
Fall Time	t _f			-	13	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s				l		
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	3.3	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	13	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S	$_{\rm S} = 3.3 \text{ A}, V_{\rm GS} = 0 \text{ V}^{\rm b}$	-	-	1.6	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 {}^{\circ}\text{C}, \ I_F = 3.3 \text{A}, \ \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$		-	270	600	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	1.4	3.0	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				1 2)	

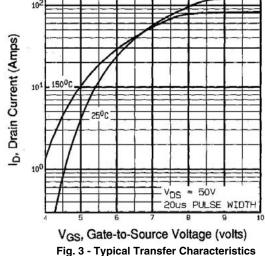
- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



V_{DS}, Drain-to-Source Voltage (volts) Fig. 1 - Typical Output Characteristics, T_C = 25 °C



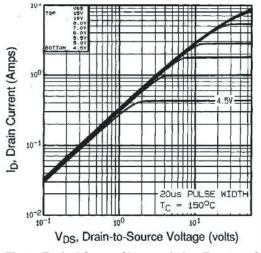


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

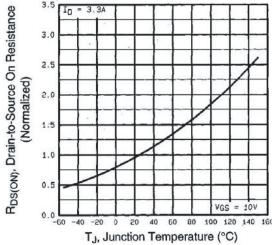


Fig. 4 - Normalized On-Resistance vs. Temperature



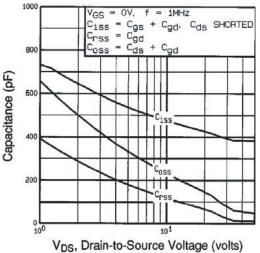


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

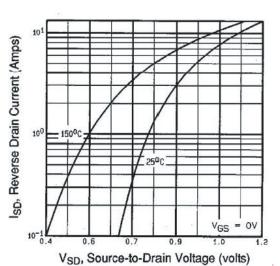


Fig. 7 - Typical Source-Drain Diode Forward Voltage

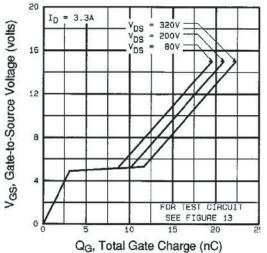


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

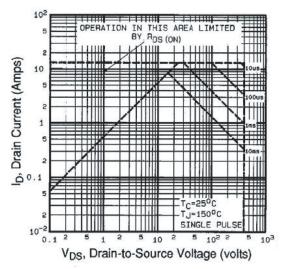


Fig. 8 - Maximum Safe Operating Area



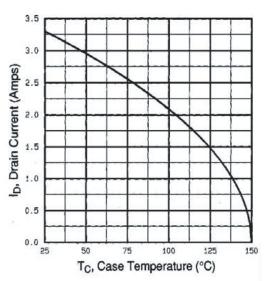


Fig. 9 - Maximum Drain Current vs. Case Temperature

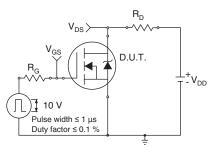


Fig. 10a - Switching Time Test Circuit

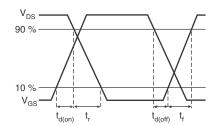


Fig. 10b - Switching Time Waveforms

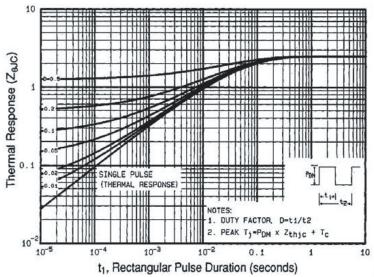


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

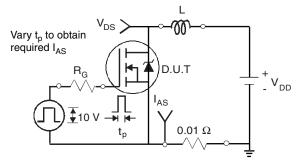


Fig. 12a - Unclamped Inductive Test Circuit

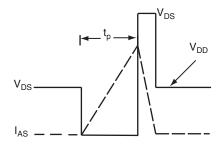


Fig. 12b - Unclamped Inductive Waveforms



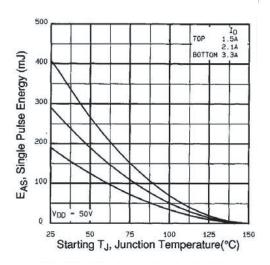


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

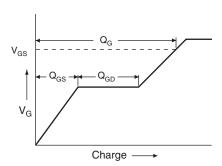


Fig. 13a - Basic Gate Charge Waveform

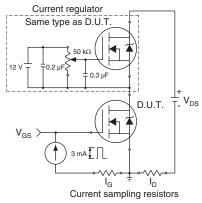
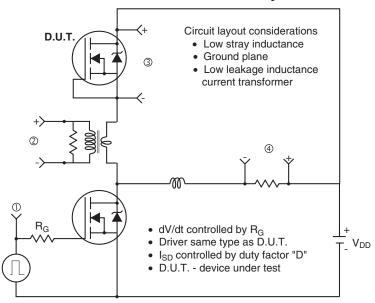
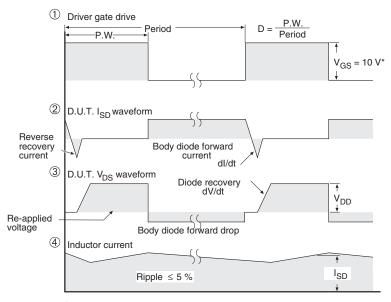


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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